

Substitute Form PTO-1449 (Modified) U.S. Department of Commerce Patent and Trademark Office Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))	Attorney's Docket No. 02052-104001	Application No. 09/815,275
Applicant Manus P. HENRY et al.		
Filing Date March 23, 2001		Group Art Unit

U.S. Patent Documents

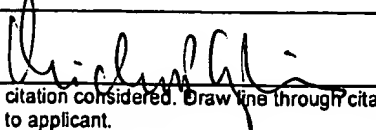
Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
an	AA	4,926,364	05/15/1990	Brotherton	702	179	
I	AB	5,570,300	10/29/1996	Henry et al.	702	48	
I	AC	5,680,409	10/21/1997	Qin et al.	714	799	
I	AD	5,774,378	06/1998	Yang	702	104	
an	AE	5,850,625	12/05/1998	Maren et al.	702	93	

Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
MN	/ AF	WO 93/21505	28 OCT 1993	PCT				✓
MN	/ AG	EP 0827096	04 MAR 1998	EUROPE				✓

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
an	AH	Atia et al., "Self-Validating Temperature Sensor Implemented in FPGAs", Oxford University Dept. of Engineering Science, 1995, pp. 321-330.
I	AI	Henry et al., "The Self-Validating Sensor: Rationale, Definitions and Examples", Dept. of Engineering Science, Univ. of Oxford, Vol. 1, No. 4, 1993, pp. 585-610.
I	AJ	J. C.-Y. Yang et al., "Control using self-validating sensors", Department of Engineering Science, Univ. of Oxford, Vol. 18, No. 1, 1996, pp. 15-23.
I	AK	Kresta et al., "Multivariate Statistical Monitoring of Process Operating Performance", Chemical Engineering Dept., McMaster Univ. Ontario, Vol. 69, Feb. 1991, pp. 35-47.
I	AL	MacGregor et al., "Statistical Process Control of Multivariate Processes", Chemical Engineering Dept., McMaster Advanced Control Consortium, McMaster Univ. Vol. 3, No. 3, 1995, pp. 403-414.
I	AM	MacGregor J. F. et al., 1991, Multivariate Statistical Methods in Process Analysis and Control. AIChE Symposium Proceedings of the Fourth International Conference on Chemical Process Control, AIChE Pub. No. P-67, New York, pp. 79-99.
I	AN	McFarlane R.C. et al., "Dynamic Simulator for a Model IV Fluid Catalytic Cracking Unit, American Institute of Chemical Engineering, Chicago, IL, 14 Nov. 1990, pp. 1-79.
I	AO	Moffat R.J., 1982, Contributions to the theory of single sample uncertainty analysis. ASME Journal of Fluids Engineering, Vol. 104, June 1982, pp. 250-260.
I	AP	Morud T.E., 1996, Multivariate Statistical Process Control; Example from the Chemical Process Industry, Journal of Chemometrics, Vol. 10, Nos. 5 & 6, pp. 669-675.
I	AQ	Qin et al., "Self-Validating Inferential Sensor for Emission Monitoring", Dept. of Chemical Engineering, Univ. of Texas, June 1997, pp. 473-477.
an	AR	Yang J.C.-Y.; 1994, "Self-validating Sensors", Dr. of Phil. Thesis, Department of Engineering Science, Univ. of Oxford.

Examiner Signature 	Date Considered 2/18/04
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	
Substitute Disclosure Form (PTO-1449)	